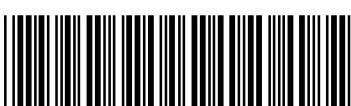


<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10720636	ZEIDMAN, ROBERT M.
	<b>Examiner</b>	<b>Art Unit</b>
	Rutten, J. Derek	2192

## SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

## SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
717/110,120,123,136,137; 434/118,367; 714/2 - text search only - see search history printout	7/24/07	/jdr/
EAST (US-PGPUB; USPAT; EPO; JPO; IBM_TDB; DERWENT) - see search history printout	7/24/07	/jdr/
EAST (US-PGPUB; USPAT; EPO; JPO; IBM_TDB; DERWENT)	5/14/08	/jdr/
EAST (US-PGPUB; USPAT; EPO; JPO; IBM_TDB; DERWENT) - see search history printout	5/20/08	/jdr/
717/110,120,123,136,137; 434/118,367; 714/2 - text search only - see search history printout	5/20/08	/jdr/
ACM (portal.acm.org), IEEE (ieeexplore.ieee.org) - see search history printout	5/21/08	/jdr/
Tuan Dam (consulted re. allowable subj. matter)	5/14/08	/jdr/

## INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
717	123		
434	118,367	3/27/08	/jdr/